MOSFET – Power, N-Channel, SUPERFET III, Easy Drive

650 V, 12 A, 260 mΩ

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advance technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET is very suitable for various power system miniaturization and higher efficiency.

Features

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ. $R_{DS(on)} = 222 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 24 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 248 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

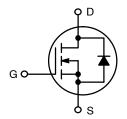
- Telecom / Server Power Supplies
- Industrial Power Supplies
- UPS / Solar



ON Semiconductor®

www.onsemi.com

V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	260 mΩ @ 10 V	12 A



POWER MOSFET



D²-PAK CASE 418AJ

MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K = Lot

FCB260N65S3 = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise specified)

Symbol	Parame	Value	Unit	
V_{DSS}	Drain to Source Voltage	650	V	
V_{GSS}	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
I _D	Drain Current	Continuous (T _C = 25°C)	12	Α
		Continuous (T _C = 100°C)	7.6	
I _{DM}	Drain Current	Pulsed (Note 1)	30	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		57	mJ
I _{AS}	Avalanche Current (Note 1)		2.3	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		0.9	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)	20		
P_{D}	Power Dissipation	(T _C = 25°C)	90	W
	Derate Above 25°C		0.72	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
 2. $I_{AS}=2.3$ A, $R_G=25$ Ω , starting $T_J=25^{\circ}C$.
 3. $I_{SD}\leq 6$ A, di/dt ≤ 200 A/ μ s, $V_{DD}\leq 400$ V, starting $T_J=25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	1.39	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 4)	40	

^{4.} Device on 1 in² pad 2 oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Reel Size	Tape Width	Shipping [†]
FCB260N65S3	FCB260N65S3	D ² -PAK	330 mm	24 mm	800 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS	•	•	•	•	
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650			V
		$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$	700			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		0.66		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 520 V, T _C = 125°C		0.77		
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V			±100	nA
ON CHARACTE	ERISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.29 \text{ mA}$	2.5		4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 6 A		222	260	mΩ
9FS	Forward Transconductance	V _{DS} = 20 V, I _D = 6 A		7.4		S
DYNAMIC CHA	RACTERISTICS	•	•	•	•	
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz		1010		pF
C _{oss}	Output Capacitance	7		25		pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		248		pF
C _{oss(er.)}	Energy Related Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		33		pF
Q _{g(tot)}	Total Gate Charge at 10 V	V _{DS} = 400 V, I _D = 6 A, V _{GS} = 10 V		24		nC
Q _{gs}	Gate to Source Gate Charge	(Note 5)		6.1		nC
Q_{gd}	Gate to Drain "Miller" Charge			9.7		nC
ESR	Equivalent Series Resistance	f = 1 MHz		8.7		Ω
SWITCHING CH	HARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 6 \text{ A},$		18		ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ (Note 5)		18		ns
t _{d(off)}	Turn-Off Delay Time	7		49		ns
t _f	Turn-Off Fall Time	7		12		ns
SOURCE-DRAI	N DIODE CHARACTERISTICS	•	•	•	•	
I _S	Maximum Continuous Source to Drain Diode Forward Current				12	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current				30	Α
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 6 A			1.2	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 6 A,		251		ns
Q _{rr}	Reverse Recovery Charge	dl _F /dt = 100 A/μs		3.4		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{5.} Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

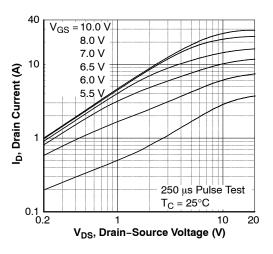


Figure 1. On-Region Characteristics

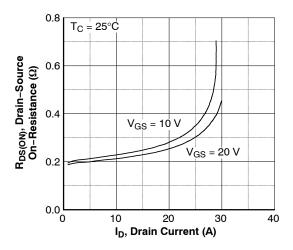


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

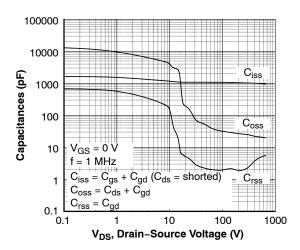


Figure 5. Capacitance Characteristics

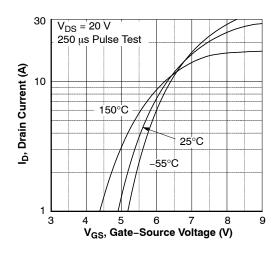


Figure 2. Transfer Characteristics

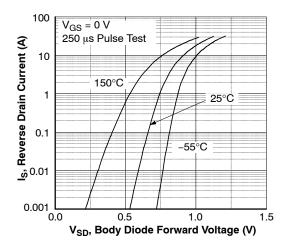


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

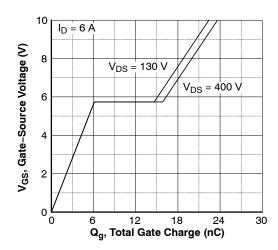


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

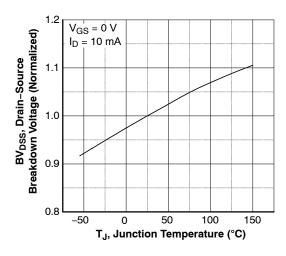


Figure 7. Breakdown Voltage Variation vs. Temperature

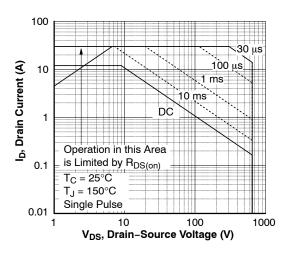


Figure 9. Maximum Safe Operating Area

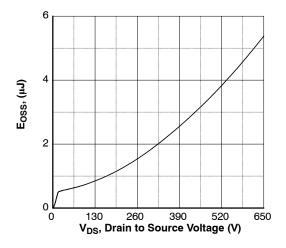


Figure 11. $E_{\mbox{OSS}}$ vs. Drain to Source Voltage

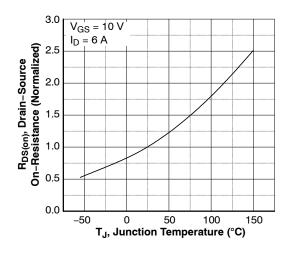


Figure 8. On–Resistance Variation vs. Temperature

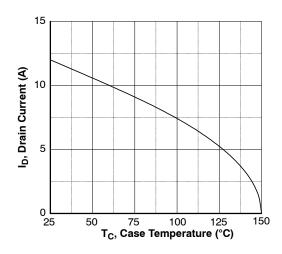


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

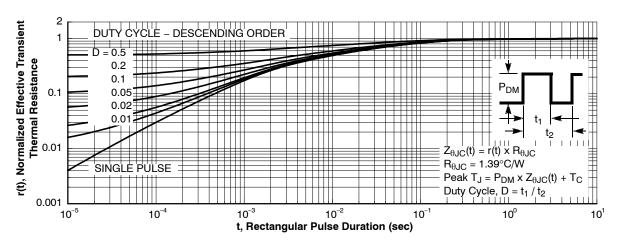


Figure 12. Transient Thermal Response Curve

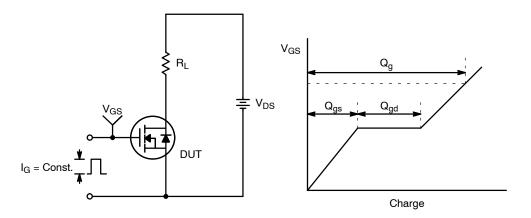


Figure 13. Gate Charge Test Circuit & Waveform

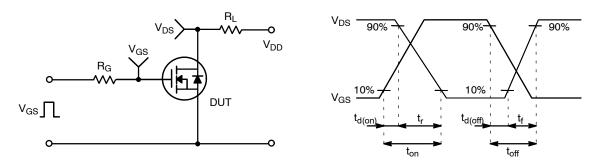


Figure 14. Resistive Switching Test Circuit & Waveforms

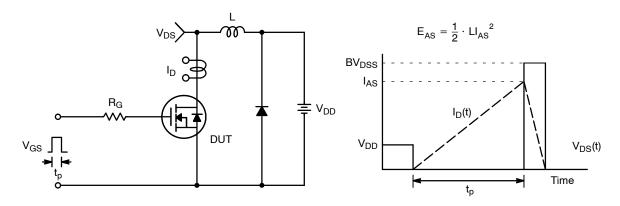


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

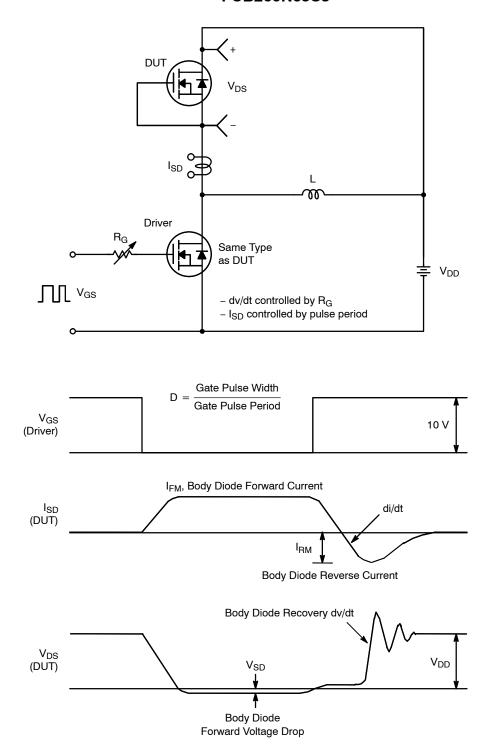


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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0.366

0.169

0.100 PITCH

0.436





0.653

2x 0.063

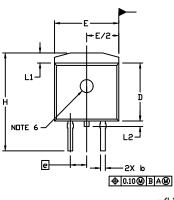
D²PAK-3 (TO-263, 3-LEAD) CASE 418AJ ISSUE E

DATE 25 OCT 2019

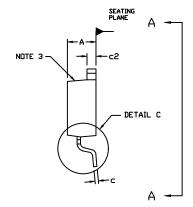
NOTES:

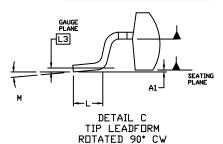
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: INCHES
- 3. CHAMFER OPTIONAL.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH.
 MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE.
 THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST
 EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
- 6. OPTIONAL MOLD FEATURE.
- 7. ①,② ... DPTIONAL CONSTRUCTION FEATURE CALL DUTS.

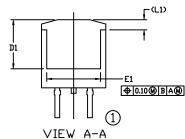
	INCHES		MILLIN	ETERS
DIM	MIN.	MAX.	MIN.	MAX.
Α	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
С	0.012	0.029	0.30	0.74
c2	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260		6.60	
Ε	0.380	0.420	9.65	10.67
E1	0.245		6.22	
6	0.100 BSC		2.54 BSC	
Н	0.575	0.625	14.60	15.88
٦	0.070	0.110	1.78	2.79
L1		0.066	-	1.68
L2		0.070		1.78
L3	0.010 BSC		0.25 BSC	
М	-8*	8*	-8*	8*

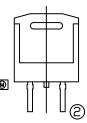


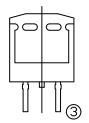
RECOMMENDED MOUNTING FOOTPRINT

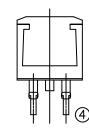












VIEW A-A

OPTIONAL CONSTRUCTIONS

XXXXXX = Specific Device Code A = Assembly Location

\text{WL} = \text{Wafer Lot} \\ Y = \text{Year} \\ \text{WW} = \text{Work Week} \\ \text{W} = \text{Week Code (SSG)} \\ \text{M} = \text{Month Code (SSG)} \\ \text{Mo

M = Month Code (SSG)
G = Pb-Free Package
AKA = Polarity Indicator

GENERIC MARKING DIAGRAMS*

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:

98AON56370E

Standard

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PAGE 1 OF 1

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Rectifier

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